



Docket No. NEC2320-USDIV  
SAI.023DIV

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re patent application of

Allowed: July 1, 2004

Junya ISHII

Confirmation No. 5980

Application No.: 10/660,753

Group Art Unit: 2825

Filing Date: September 12, 2003

Examiner: Lee, Calvin

For: SEMICONDUCTOR DEVICE AND TEST METHOD FOR MANUFACTURING SAME

Honorable Commissioner of Patents  
Alexandria, Virginia 22313-1450

**SUBMISSION OF CORRECTED FORMAL DRAWING**

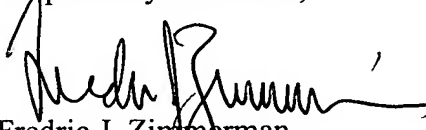
Sir:

Submitted herewith is corrected formal drawing for Figure 1 for the above-identified patent application, as requested by Examiner's Amendment/Form PTOL-37, dated July 1, 2004.

Approval and acknowledgment of receipt are respectfully requested.

Date: 7/15/04

Respectfully submitted,

  
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